

In the Specification:

Replace the paragraph on page 4, lines 12-22, with --

*B1*  
*with this*  
The use of external test connecting contact points allow  
internal chip signals to be seen and the timing to be *how* *long*  
determined accurately. For this purpose, a reference signal is  
selectively applied to one of the external test connecting  
contact points such that it can be passed on via a route *not shown in fig.*  
within the component to a circuit point which is not *NA shown in fig.*  
externally accessible. *External* Signals which are to be measured or  
are to be analyzed can in each case be selectively applied  
such that they can be passed on via routes within the  
component from circuit points which are not externally  
accessible to the other test connecting contact points. --